Notice of References Cited Application/Control No. 10/698,249 Examiner Pablo N. Tran Applicant(s)/Patent Under Reexamination BLACK ET AL. Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,862,432	03-2005	Kim, Hong Joo	455/80
*	В	US-6,985,760	01-2006	Hosonuma, Yoshimasa	455/575.3
*	O	US-5,335,368	08-1994	Tamura, Yoshiharu	455/575.7
*	۵	US-6,297,778	10-2001	Phillips et al.	343/702
*	Е	US-6,714,773	03-2004	Ishida, Takayasu	455/272
*	F	US-2004/0192406	09-2004	Okazaki et al.	455/569.1
*	G	US-6,813,481	11-2004	lde, Yoshiyuki	455/129
*	Н	US-5,892,483	04-1999	Hayes et al.	343/729
*	ı	US-5,739,792	04-1998	Hassemer et al.	343/702
*	٦	US-2003/0011531	01-2003	Saito et al.	343/895
*	K	US-2004/0113849	06-2004	Jarmuszewski et al.	343/702
*	٦	US-5,963,871	10-1999	Zhinong et al.	455/552.1
*	М	US-6,122,524	09-2000	Goerke, Thomas	455/552.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	NON-FATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	\ \							
	w							
	x							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | BLACK ET AL. | Examiner | Art Unit | Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,597,930	07-2003	Nakamura et al.	455/575.1
*	В	US-6,002,943	12-1999	Irvin et al.	455/522
*	С	US-5,818,392	10-1998	Oka et al.	343/702
*	D	US-6,738,603	05-2004	Saito, Tetsuya	455/90.1
*	Е	US-5,374,937	12-1994	Tsunekawa et al.	343/702
*	F	US-6,188,918	02-2001	Cockson, Mark G.	455/575.7
*	G	US-5,635,943	06-1997	Grunwell, Randall L.	343/702
*	Н	US-6,611,691	08-2003	Zhou et al.	455/550.1
*	_	US-6,097,934	08-2000	Spall et al.	455/575.7
*	7	US-6,229,489	05-2001	Holshouser et al.	343/702
*	К	US-5,969,683	10-1999	Hayes et al.	343/702
*	٦	US-6,008,765	12-1999	Davidson et al.	343/702
*	М	US-5,479,178	12-1995	Ha, Dong-In	343/702

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s			*****		
	Т					

NON-PATENT DOCUMENTS

		NON-I ATEN DOCUMENTO
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/698,249 Examiner Pablo N. Tran Applicant(s)/Patent Under Reexamination BLACK ET AL. Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,923,297	07-1999	Kim et al.	343/702
*	В	US-5,794,158	08-1998	Itoh, Ryoh	455/575.7
	С	US-			
	D	US-			
	E	US-			
	F	US-	<u> </u>		
	G	US-			,
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.